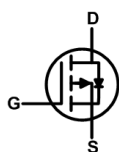


Description

The SI2307 is the high cell density trenched P-ch MOSFETs, which provides excellent RDSON and efficiency for most of the small power switching and load switch applications.

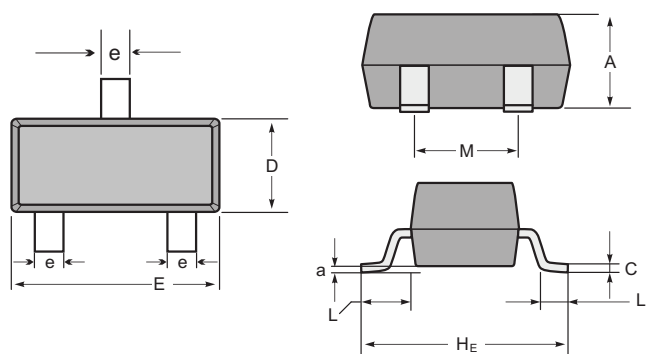
The SI2307 meet the RoHS and Green Product requirement with full function reliability approved.

Green Device Available
Super Low Gate Charge
Excellent CdV/dt effect decline
Advanced high cell density Trench technology



Product Summary

BVDSS	RDSON	ID
-30V	65mΩ	-3A



SOT-23 mechanical data

UNIT		A	C	D	E	HE	e	M	L	L1	a
mm	max	1.1	0.15	1.4	3.0	2.6	0.5	1.95	0.55 (ref)	0.36 (ref)	0.0
	min	0.9	0.08	1.2	2.8	2.2	0.3	1.7			0.15
mil	max	43	6	55	118	102	20	77	22 (ref)	14 (ref)	0.0
	min	35	3	47	110	87	12	67			6

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-30	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D@T_A=25^\circ\text{C}$	Continuous Drain Current	-3	A
$I_D@T_A=70^\circ\text{C}$	Continuous Drain Current	-1.6	A
I_{DM}	Pulsed Drain Current ²	-10	A
$P_D@T_A=25^\circ\text{C}$	Total Power Dissipation ³	1.4	W
$P_D@T_A=70^\circ\text{C}$	Total Power Dissipation ³	0.9	W
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ\text{C}$

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	---	105	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹ (t ≤ 10s)	---	---	$^\circ\text{C/W}$

SI2307

Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Off Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-30	---	---	V
ΔBV _{DSS} /ΔT _J	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =-1mA	---	-0.02	---	V/°C
I _{DSS}	Drain-Source Leakage Current	V _{DS} =-27V , V _{GS} =0V , T _J =25°C	---	---	-1	uA
		V _{DS} =-24V , V _{GS} =0V , T _J =125°C	---	---	-10	uA
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V	---	---	±100	nA

On Characteristics

R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =-10V , I _D =-3A	---	65	95	mΩ
		V _{GS} =-4.5V , I _D =-2A	---	110	145	mΩ
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =-250uA	-1.0	-1.6	-2.5	V
ΔV _{GS(th)}	V _{GS(th)} Temperature Coefficient		---	-2.8	---	mV/°C
g _{fs}	Forward Transconductance	V _{DS} =-10V , I _D =-1A	---	3	---	S

Dynamic and switching Characteristics

Q _g	Total Gate Charge ^{2, 3}	V _{DS} =-24V , V _{GS} =-4.5V , I _D =-2A	---	2.5	---	nC
Q _{gs}	Gate-Source Charge ^{2, 3}		---	0.1	---	
Q _{gd}	Gate-Drain Charge ^{2, 3}		---	1.8	---	
T _{d(on)}	Turn-On Delay Time ^{2, 3}	V _{DD} =-15V , V _{GS} =-10V , R _G =6Ω I _D =-1A	---	6.1	---	ns
T _r	Rise Time ^{2, 3}		---	8.7	---	
T _{d(off)}	Turn-Off Delay Time ^{2, 3}		---	33.2	---	
T _f	Fall Time ^{2, 3}		---	3.7	---	
C _{iss}	Input Capacitance	V _{DS} =-15V , V _{GS} =0V , F=1MHz	---	226	---	pF
C _{oss}	Output Capacitance		---	39	---	
C _{rss}	Reverse Transfer Capacitance		---	29	---	
R _g	Gate resistance	V _{GS} =0V, V _{DS} =0V, F=1MHz	---	9.5	---	Ω

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I _S	Continuous Source Current	V _G =V _D =0V , Force Current	---	---	-3.3	A
I _{SM}	Pulsed Source Current		---	---	-6.6	A
V _{SD}	Diode Forward Voltage	V _{GS} =0V , I _S =-1A , T _J =25°C	---	---	-1.2	V

Note :

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
2. The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%.
3. Essentially independent of operating temperature.

RATING AND CHARACTERISTIC CURVES (SI2307)

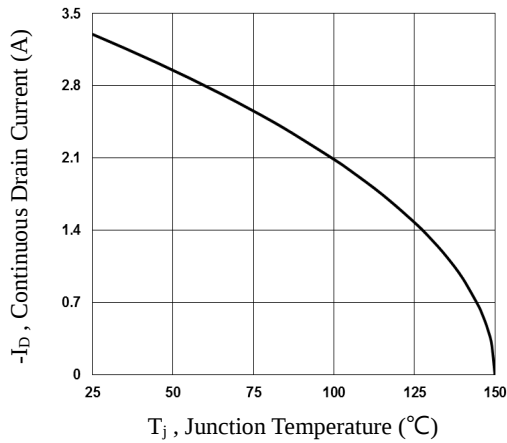


Fig.1 Continuous Drain Current vs. T_c

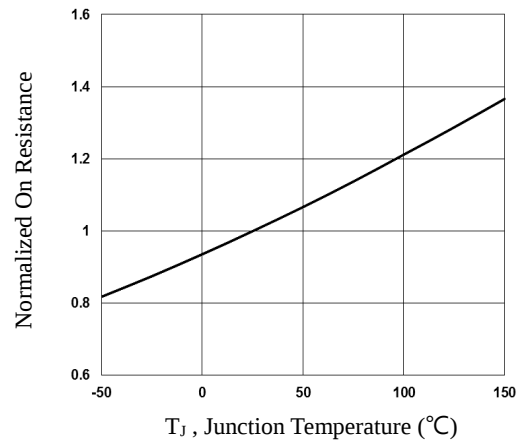


Fig.2 Normalized $R_{DS(on)}$ vs. T_J

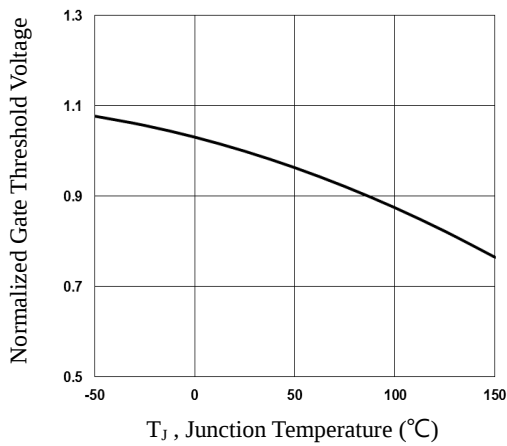


Fig.3 Normalized V_{th} vs. T_J

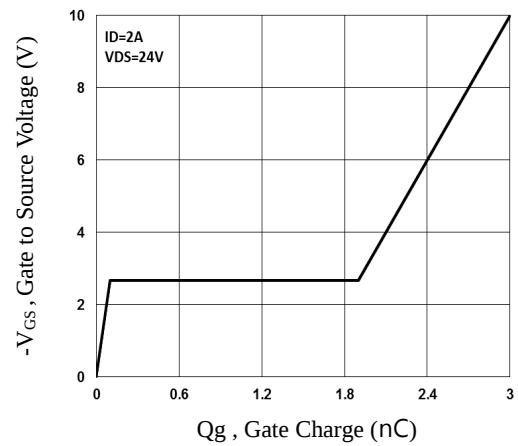


Fig.4 Gate Charge Waveform

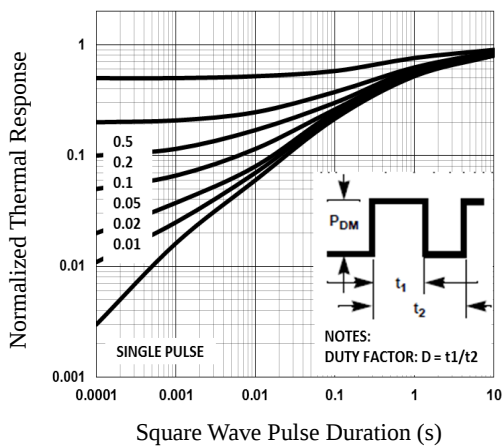


Fig.5 Normalized Transient Impedance

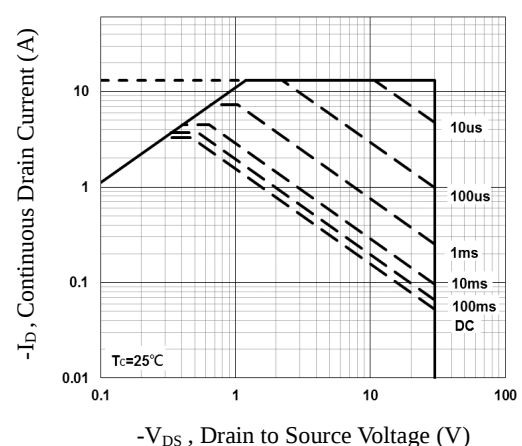


Fig.6 Maximum Safe Operation Area

RATING AND CHARACTERISTIC CURVES (SI2307)

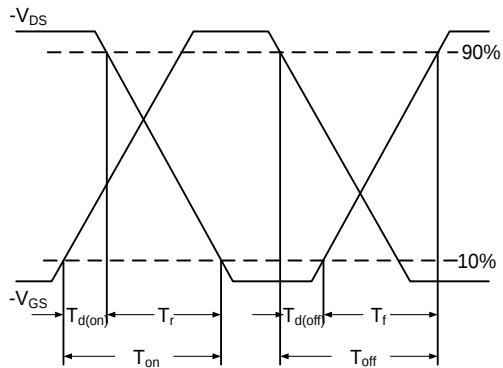


Fig.7 Switching Time Waveform

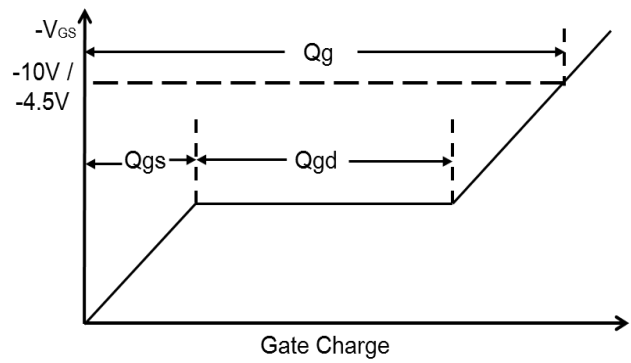


Fig.8 Gate Charge Waveform